

Figure 1

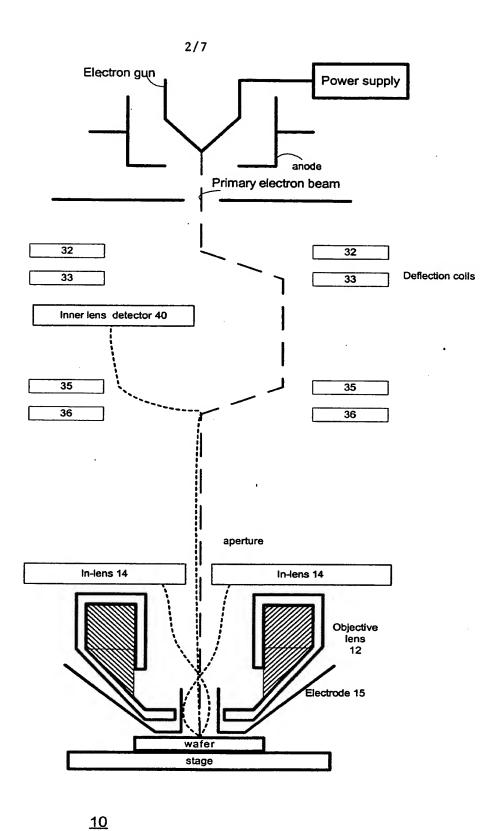
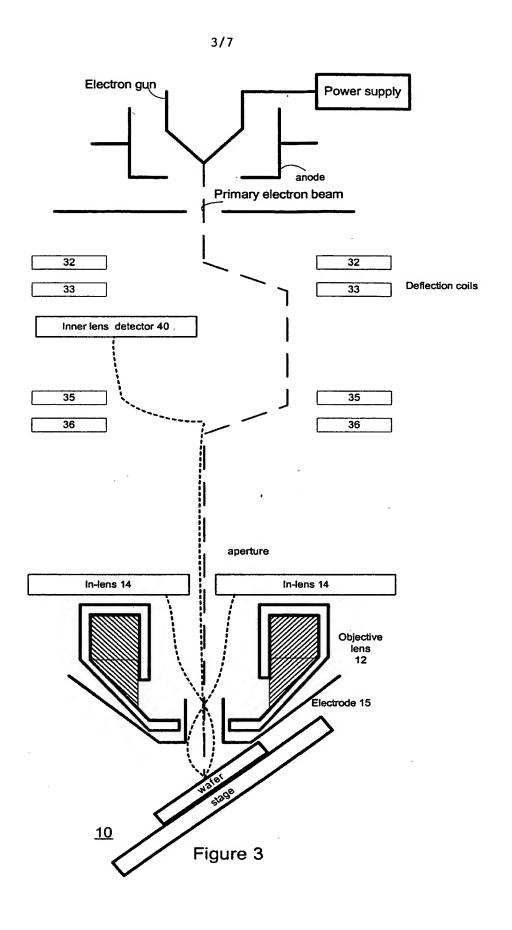
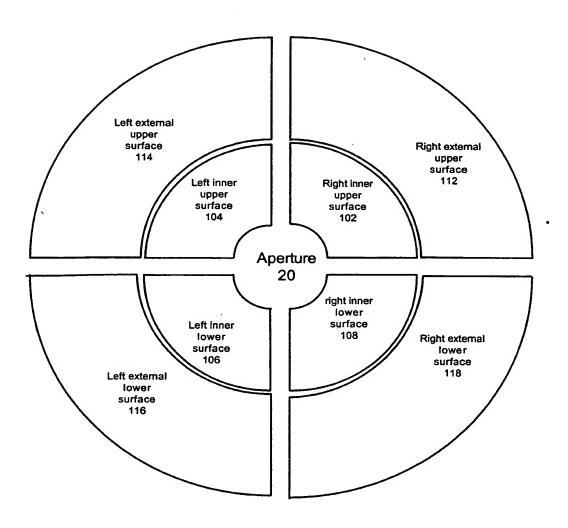


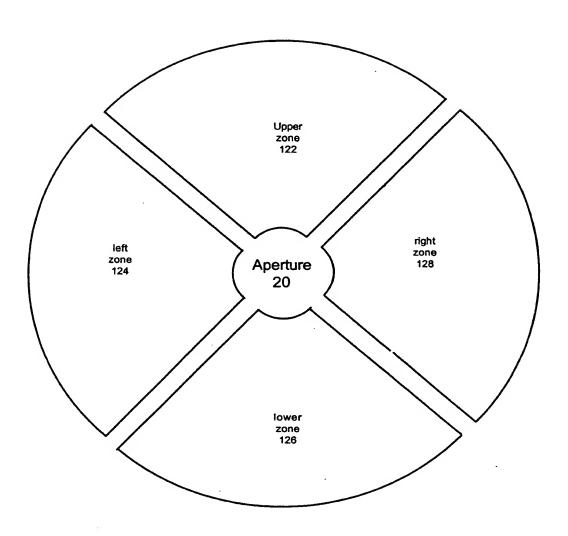
Figure 2



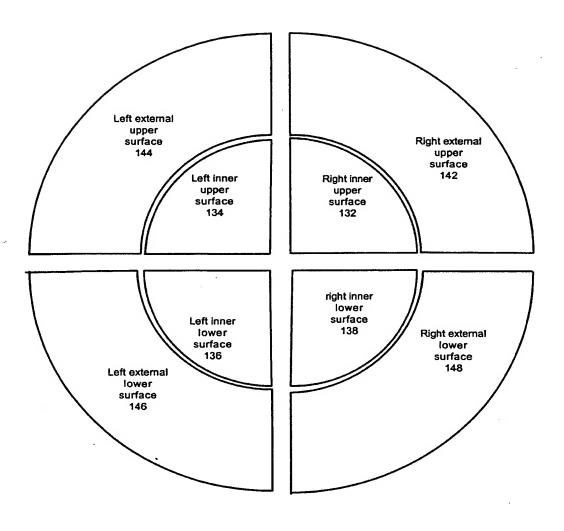


<u>14</u>

Figure 4A



14 Figure 4B



40 Figure 4C

directing a primary electron beam, through a column, to interact with an inspected object.

210

directing, by introducing a substantial electrostatic field, electrons reflected or scattered from the inspected objects towards multiple interior detectors, whereas at least some of the directed electrons are reflected or scattered at small angle in relation to the inspected object 220

receiving detection signals from at least one interior detector 230

processing the received detection signals to provide an indication about a defect or a process variation.

240

200

## Figure 5